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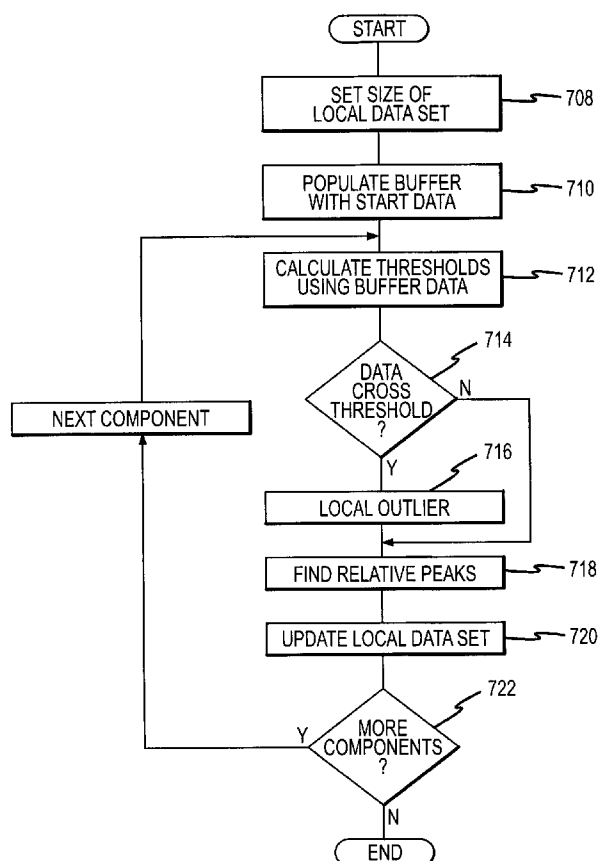
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(54) Title: METHODS AND APPARATUS FOR LOCAL OUTLIER DETECTION



(57) Abstract: A method and apparatus for data analysis according to various aspects of the present invention is configured to identify statistical outliers in test data for components, including local outliers representing outliers within subsets of larger data populations.

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